

NDH831N

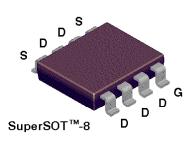
N-Channel Enhancement Mode Field Effect Transistor

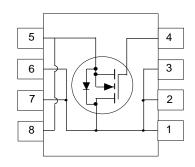
General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and portable electronics where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- 5.8A, 20V. $R_{DS(ON)} = 0.03\Omega$ @ $V_{GS} = 4.5V$ $R_{DS(ON)} = 0.04\Omega$ @ $V_{GS} = 2.7V$.
- High density cell design for extremely low R_{DS(ON)}.
- Enhanced SuperSOT[™]-8 small outline surface mount package with high power and current handling capability.





Absolute Maximum Ratings T. = 25°C unless otherwise noted

Symbol	Parameter	NDH831N	Units	
V _{DSS}	Drain-Source Voltage		20	V
/ _{GSS}	Gate-Source Voltage		8	V
D	Drain Current - Continuous	(Note 1a)	5.8	А
	- Pulsed		20	
P_{D}	Maximum Power Dissipation	(Note 1a)	1.8	W
		(Note 1b)	1	
		(Note 1c)	0.9	
J,T _{STG}	Operating and Storage Temperature Range		-55 to 150	∞
HERMA	L CHARACTERISTICS	·		
R _{BJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	70	°C/W
R _{⊕C}	Thermal Resistance, Junction-to-Case	(Note 1)	20	°CM

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V				1	μA
			T _J = 55°C			10	μΑ
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		0.4	0.6	1	V
			T _J = 125°C	0.3	0.35	0.8	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 5.8 \text{ A}$			0.022	0.03	W
			T _J = 125°C		0.03	0.54	
		$V_{GS} = 2.7 \text{ V}, I_D = 5 \text{ A}$			0.027	0.04	
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	20			Α	
		$V_{GS} = 2.7 \text{ V}, V_{DS} = 5 \text{ V}$		5			
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_{D} = 5.8 \text{ A}$		14		S	
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, \ V_{GS} = 0 \text{ V},$		720		pF	
C _{oss}	Output Capacitance	f = 1.0 MHz			430		pF
C _{rss}	Reverse Transfer Capacitance				155		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 6 \text{ V}, I_{D} = 1 \text{ A},$			10	20	ns
t _r	Turn - On Rise Time	$V_{\rm GEN}$ = 4.5 V, $R_{\rm GEN}$ = 6 Ω			30	50	ns
t _{D(off)}	Turn - Off Delay Time				55	80	ns
t _f	Turn - Off Fall Time				20	40	ns
Q_g	Total Gate Charge	$V_{DS} = 5 V$,			19.5	28	nC
Q_{gs}	Gate-Source Charge	$I_D = 5.8 \text{ A}, V_{GS} = 4.5 \text{ V}$			1.8		nC
Q_{gd}	Gate-Drain Charge				5.5		nC

ELECTRICAL CHARACTERISTICS (T _A = 25°C unless otherwise noted)									
Symbol	Parameter Conditions Min Typ Max Units								
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS									
Is	Maximum Continuous Drain-Source Diode			1.5	Α				
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.5 \text{ A} \text{ (Note 2)}$		0.75	1.2	V			

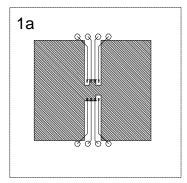
Notes:

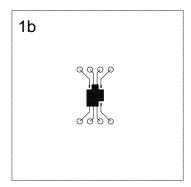
1. R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.

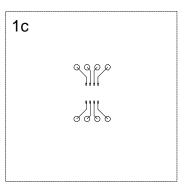
$$P_D(t) = \frac{T_J - T_A}{R_{\theta J} \oint t^1} = \frac{T_J - T_A}{R_{\theta J} \oint R_{\theta C} \oint t^1} = I_D^2(t) \times R_{DS(ON) \theta T_J}$$

Typical $R_{_{\text{qJA}}}$ using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 70°C/W when mounted on a 1 in² pad of 2oz copper.
- b. 125°C/W when mounted on a 0.026 in² pad of 2oz copper.
- c. 135°C/W when mounted on a 0.005 in² pad of 2oz copper.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

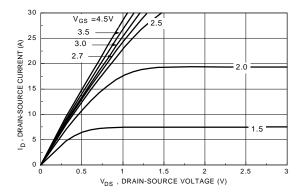


Figure 1. On-Region Characteristics.

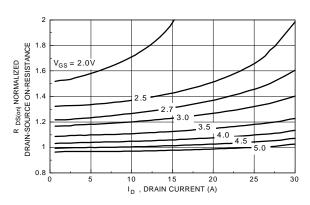


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

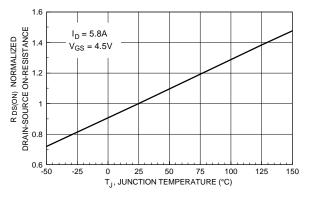


Figure 3. On-Resistance Variation with Temperature.

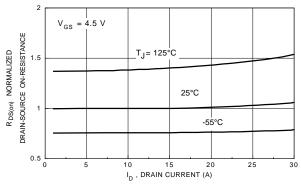


Figure 4. On-Resistance Variation with Drain Current and Temperature.

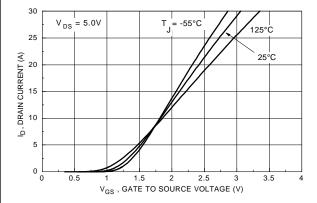


Figure 5. Transfer Characteristics.

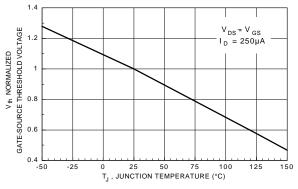


Figure 6. Gate Threshold Variation with Temperature.

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Typical Electrical Characteristics

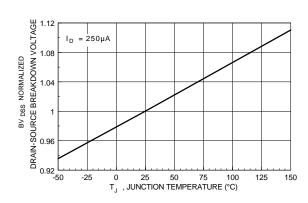


Figure 7. Breakdown Voltage Variation with Temperature.

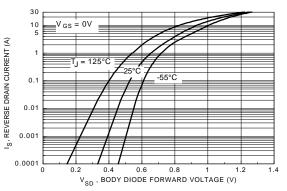


Figure 8. Body Diode Forward Voltage Variation with Current and Temperature.

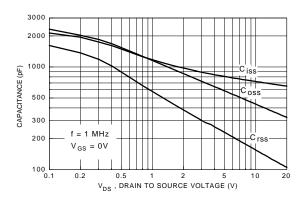


Figure 9. Capacitance Characteristics.

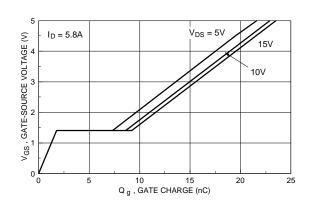


Figure 10. Gate Charge Characteristics.

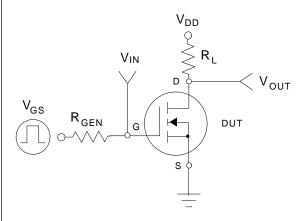


Figure 11. Switching Test Circuit

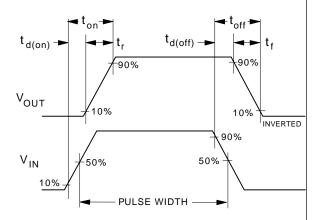


Figure 12. Switching Waveforms

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Typical Thermal Characteristics

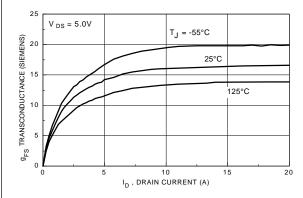
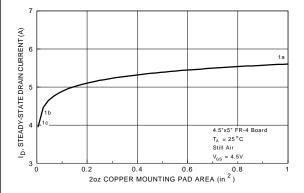


Figure 13. Transconductance Variation with Drain Current and Temperature.

Figure 14. SuperSOT[™]-8 Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area.



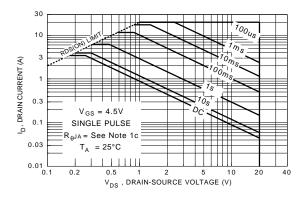


Figure 15. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

Figure 16. Maximum Safe Operating Area.

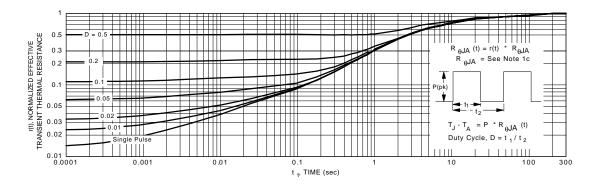
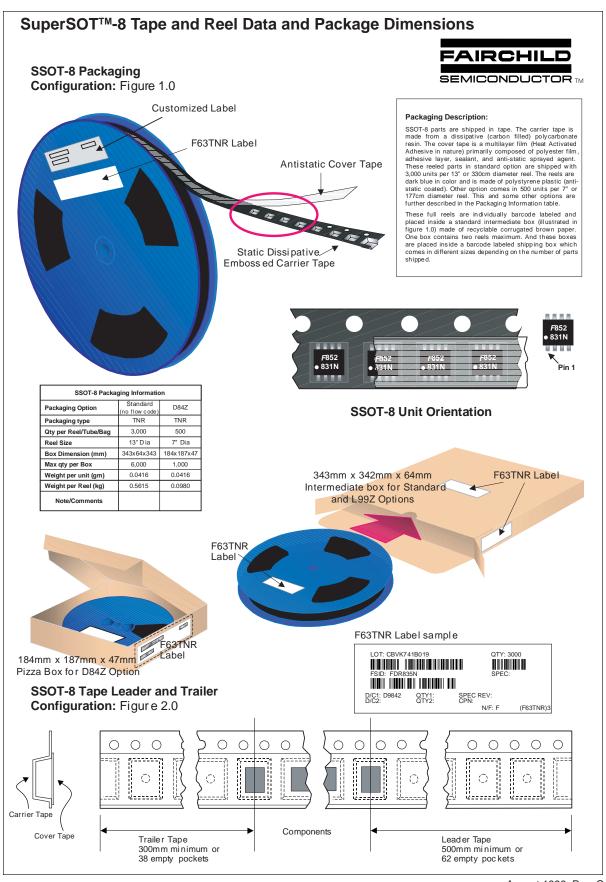
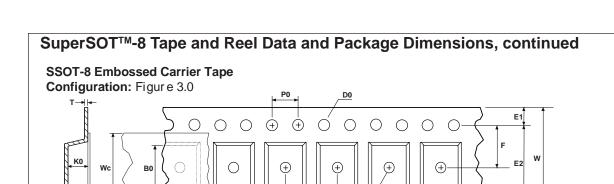


Figure 17. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.





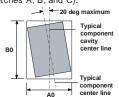


	Dimensions are in millimeter													
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	Т	Wc	Тс
SSOT-8 (12mm)	4.47 +/-0.10	5.00 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.280 +/-0.150	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



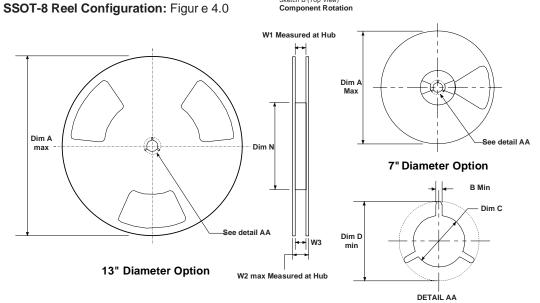
Sketch A (Side or Front Sectional View)
Component Rotation



Sketch B (Top View)
Component Rotation



Sketch C (Top View)
Component lateral movement

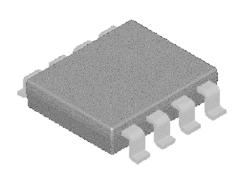


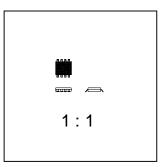
	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

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SuperSOT™-8 Tape and Reel Data and Package Dimensions, continued

SuperSOT™-8 (FS PKG Code 34, 35)

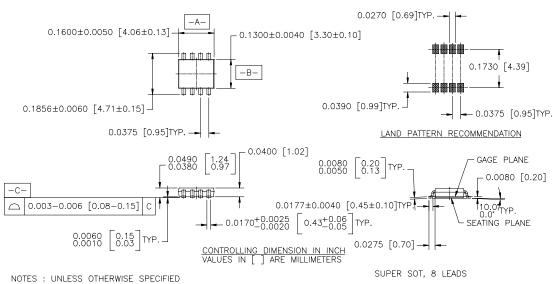




Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.0416



STANDARD LEAD FINISH TI BE 200 MICROINCHES / 5.08 MICROMETERS MINIMUM TIN/LEAD (SOLDER) ON COPPER.

2. NO JEDEC REGISTRATION AS JAN. 1996

September 1998, Rev. A

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